

Table 4: RENA-2 Specifications. Some items refer to Table 1 and other figures.

| No. | No. Specification | Conditions | Min | Typ | Max | Comments |
|-----|---------------------------------------|---|-------------------------------|-----|--------|--|
| _ | Full scale signal range | Range A, see Table 1 | 9 fC (250 keV for CZT) | | | Selection on a channel-by-channel basis of one of two full scale signal ranges. This minimum FSR must be |
| 2 | Full scale signal range | Range B, see Table 1 | 54 fC (1.5 MeV for CZT) | | | achieved in all good parts, despite absolute capacitance tolerance for fabrication process. |
| 3 | Allowable DC input | Positive polarity, see Table 1 | -100 pA | · | 5 nA | Small reverse input currents can occur in AC coupled systems, due to |
| 4 | ситепt | Negative polarity, see Table 1 | -5 nA | | 100 pA | leakage. |
| 5 | | Range A, Cap-opt A, C _d = 2 pF, see Table 1 | | | 18 aC | This is equivalent to 112 electrons, a |
| 9 | o _{inp} (total rms noise and | Range A, Cap-opt B, $C_d = 9 \text{ pF}$, see Table 1 | | | 18 aC | dynamic range of 500. |
| 7 | error, input referred) | Range B, Cap-opt A, $C_d = 2 pF$, see Table 1 | | | 54 aC | This is equivalent to 337 electrons, a |
| ∞ | | Range B, Cap-opt B, $C_d = 9 \text{ pF}$, see Table 1 | | | 54 aC | dynamic range of 1000. |

Table 4: Continued

| No. | Specification | Conditions | Min | Typ | Max | Comments |
|-----|--|--|---|---|-------------------------------|--|
| 6 | ∂σ _{inp} / ∂C _d | Range A, Cap-opt A, C _d = 2 pF, see Table 1 | | ТВD | | |
| 10 | | Range A, Cap-opt B, $C_d = 9 \text{ pF}$, see Table 1 | | ТВD | | Selectable (on a channel-by-channel basis) noise optimization by changing |
| = | | Range B, Cap-opt A, $C_d = 2 \text{ pF}$, see Table 1 | | ТВD | | control bit. Optimized for two capacitance input values. |
| 12 | | Range B, Cap-opt B, $C_d = 9 \text{ pF}$, see Table 1 | | ТВD | | |
| 13 | Minimum operating trigger threshold | Range A, see Table 1 | | | 100 aC | This is equivalent to 624 electrons. |
| 41 | requirement (applies to all channels simultaneously) | Range B, see Table 1 | | | 580 aC | This is equivalent to 3620 electrons. |
| 15 | Test signal coupling capacitance | | | 75 fF | | This implies that a 707 mV step will inject the full scale (range B) signal of 53 fC |
| 16 | Number of active channels | | 36 | | | In addition, a dummy channel for matching is at each end of array. |
| 17 | Peaking time constant | 16 selections 0-15 | 0.36, 0.39, 0.41, 0.45, 0.49, 0.54, 0.59, 0.66, 0.91, 1.08, 1.27, 1.69, 1.82, 2.80, 4.46, 38.0 µs nominal | 141, 0.45, 0 1.91, 1.08, 1 1.46, 38.0 µ | .49, 0.54,27, 1.69, s nominal | 16 selections available on a channel by channel basis |
| 18 | Power dissipation | Event rate 1 kHz, single hits | | 6mW | ТВD | Goal is 5 mW/ch, estimate 6 mW/ch with fast trigger path disabled. Channel power down available on a per channel basis. Off channels dissipate < 0.5mW each. |

Table 4: Continued

| No. Sp 19 Tc 20 De | | | | | | |
|--------------------------|--|--------------|---|---------------------------|----------------------|---|
| | Specification | Conditions | Min | Typ | Max | Comments |
| | Total dose (γ) tolerance | <50% failure | 20 kRad(Si) | | | SEU is not a concern. The radiation specs are goals to be attempted on a |
| | Destructive SEL | ТВD | | | 0 | best effort basis with standard CMOS technology, no special process. |
| 21 Ti | Timing jitter | See Table 1 | | - | 10 ns (or better) | Note that this is for input pulses of fixed amplitude - it excludes time walk due to amplitude variation. |
| 22 Di D/ | Discriminator threshold DAC number of bits | | 8 | | | |
| 23 Di D/ | Discriminator threshold DAC DNL | | 1 bit, guaranteed monotonic | eed monot | onic | |
| 24 D/ | Discriminator threshold DAC range | | Determined by external voltage input, settable from 0 up to FS signal range | y external e from 0 up | voltage o to FS | |
| Synchro S | Cycle time requirement | | 30 ns | | | |
| onous CN 92 | Setup time requirement | | 12 ns | | | direct connection to Xilinx Spartan- series FPGA (or similar) running at 32 |
| SON SON | Hold time requirement | | o ns | | | WINZ. |
| 28 | Data valid time | | 10 ns | | | |

Table 4: Continued

| No. | No. Specification | Conditions | Min | Typ | Max | Comments |
|-----|----------------------------------|--|---|---|---|---|
| 29 | EMI-critical signal standards | | LVDS or low-swing (150 mV) version | w-swing (15 | | Applies only to TRIG, RST, and ACQUIRE signals (all asynchronous) |
| 30 | 30 Analog output architecture | | Differential out with disable, to drive capacitive load only; 4 or more RENA 2000 bussed together to single A/D | out with dis tive load on 2000 busse | able, to ly; 4 or ed together | |
| 31 | 31 Analog output settling time | C _L = TBD, 12-bit settling | | | ТВD | Goal is 333 ns |
| 32 | Analog output format | | For each channel marked in the reacegister, peak detector level and (if enabled) U and V timestamp levels | annel marke k detector le and V times | For each channel marked in the read register, peak detector level and (if enabled) U and V timestamp levels | |
| 33 | Dead time per event | Event with n channels TBD to read; HIT/READ register is read and written | ТВD | TBD | TBD | Goal is 5 μs + n*(333 ns) |
| 34 | Input pad pitch | | 125 µm | | | |